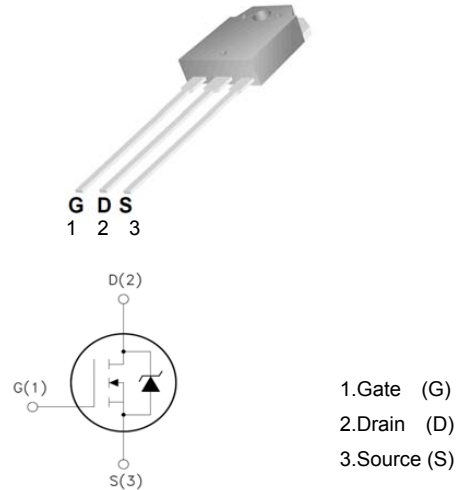


Features

- Low Intrinsic Capacitances.
- Excellent Switching Characteristics.
- Extended Safe Operating Area.
- Unrivalled Gate Charge: $Q_g = 60\text{nC}$ (Typ.).
- $BVDSS = 900\text{V}, I_D = 11\text{A}$
- $R_{DS(on)} : 1.1\Omega$ (Max) @ $V_G = 10\text{V}$
- 100% Avalanche Tested

Package

TO-3P



Absolute Maximum Ratings ($T_a = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage	900	V
I_D	Drain Current	$T_C = 25^\circ\text{C}$	11
		$T_C = 100^\circ\text{C}$	6.9
$V_{GS(TH)}$	Gate Threshold Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note1)	960	mJ
I_{AR}	Avalanche Current (note2)	11	A
P_D	Power Dissipation ($T_j = 25^\circ\text{C}$)	300	W
T_j	Junction Temperature(MAX)	150	$^\circ\text{C}$
T_{stg}	Storage Temperature	-55~+150	$^\circ\text{C}$
TL	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	-	0.42	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	-	62.5	$^\circ\text{C/W}$



Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\ \mu A$	900	--	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D=250\ \mu A$, Referenced to 25°C	--	1.02	--	V/ $^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=900\ \text{V}, V_{GS}=0V$	--	--	10	μA
		$V_{DS}=720\ \text{V}, T_C=125^\circ\text{C}$	--	--	100	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS}=30\ \text{V}, V_{DS}=0V$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS}=-30\ \text{V}, V_{DS}=0V$	--	--	-100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\ \mu A$	3.0	--	5.0	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\ \text{V}, I_D = 5.5\ \text{A}$	--	0.91	1.1	Ω
g_{FS}	Forward Trans conductance	$V_{DS} = 50\ \text{V}, I_D = 5.5\ \text{A}$ (Note4)	--	--	--	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=25\ \text{V}, V_{GS}=0\ \text{V}, f=1.0\text{MHz}$	--	2530	3290	pF
C_{oss}	Output Capacitance		--	215	280	pF
C_{rss}	Reverse Transfer Capacitance		--	23	30	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 450\ \text{V}, I_D = 11.0\ \text{A}, R_G = 25\ \Omega$ (Note 4, 5)	--	60	130	ns
t_r	Turn-On Rise Time		--	130	270	ns
$t_{d(off)}$	Turn-Off Delay Time		--	130	270	ns
t_f	Turn-Off Fall Time		--	85	180	ns
Q_g	Total Gate Charge	$V_{DS} = 720\ \text{V}, I_D = 11.0\ \text{A}, V_{GS} = 10\ \text{V}$ (Note 4, 5)	--	60	80	nC
Q_{gs}	Gate-Source Charge		--	13	--	nC
Q_{gd}	Gate-Drain Charge		--	25	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current		--	--	11.0	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current		--	--	44.0	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0\ \text{V}, I_S = 11.0\ \text{A}$	--	--	1.4	V
t_{rr}	Reverse Recovery Time	$V_{GS} = 0\ \text{V}, I_S = 11.0\ \text{A}$	--	1000	--	ns
Q_{rr}	Reverse Recovery Charge	$di/dt=100\text{A}/\mu\text{s}$	--	17.0	--	μC

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. $L = 15\text{mH}, I_{AS} = 11.0\text{A}, V_{DD} = 50\text{V}, R_G = 25\ \Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq 11.0\text{A}, di/dt \leq 200\text{A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width $\leq 300\ \mu\text{s}$, Duty cycle $\leq 2\%$
5. Essentially independent of operating temperature

Typical Characteristics

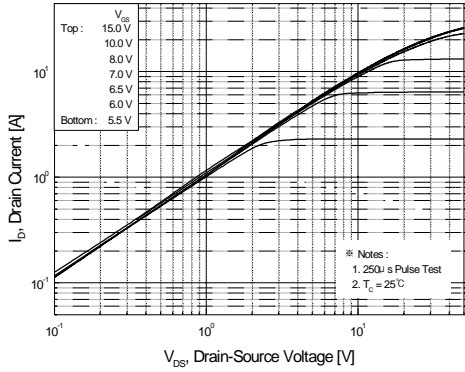


Figure 1. On-Region Characteristics

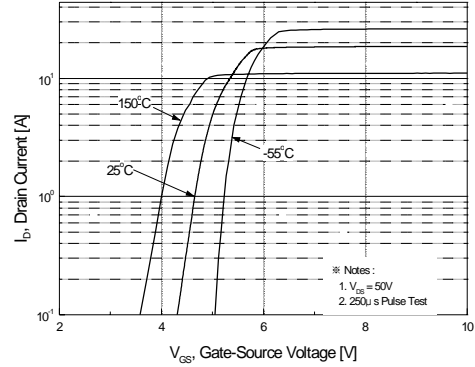


Figure 2. Transfer Characteristics

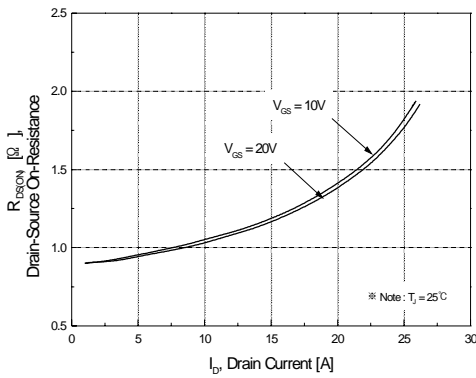


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

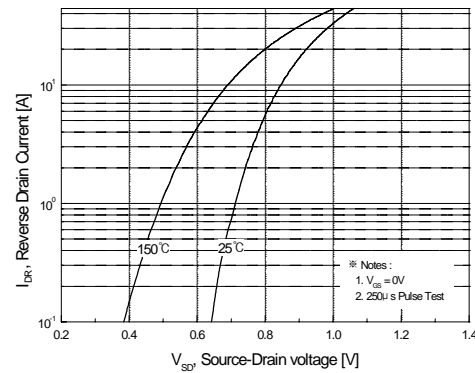


Figure 4. Body Diode Forward Voltage Variation with Source Current

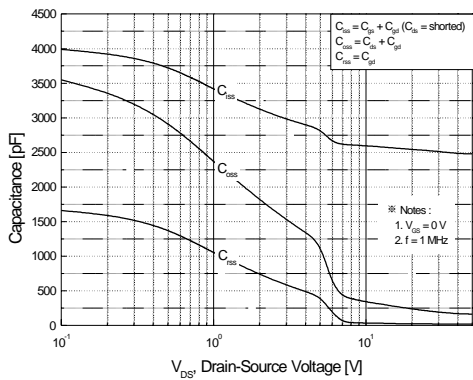


Figure 5. Capacitance Characteristics

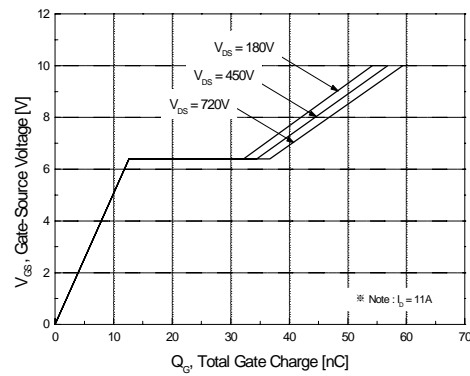


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

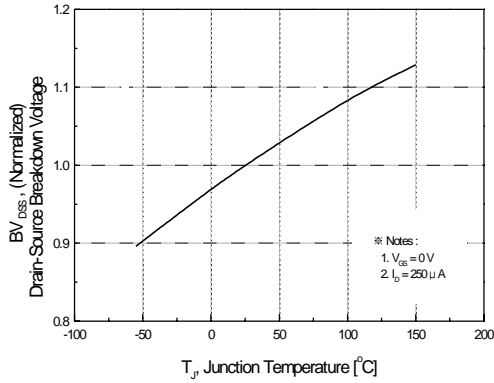


Figure 7. Breakdown Voltage Variation

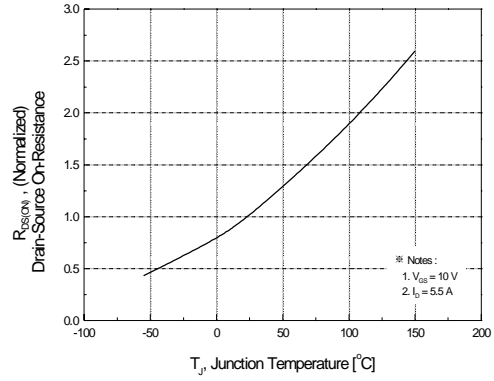


Figure 8. On-Resistance Variation

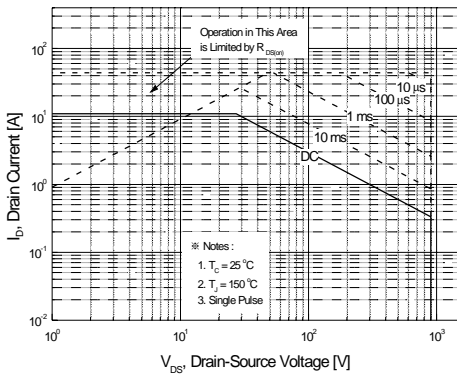


Figure 9. Maximum Safe Operating Area

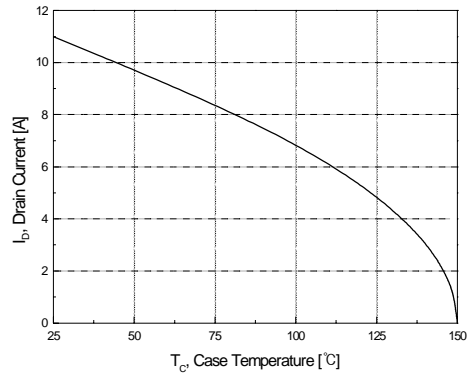


Figure 10. Maximum Drain Current vs Case Temperature

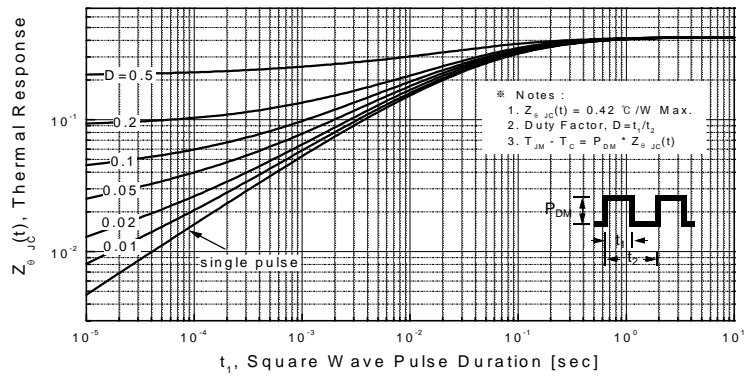
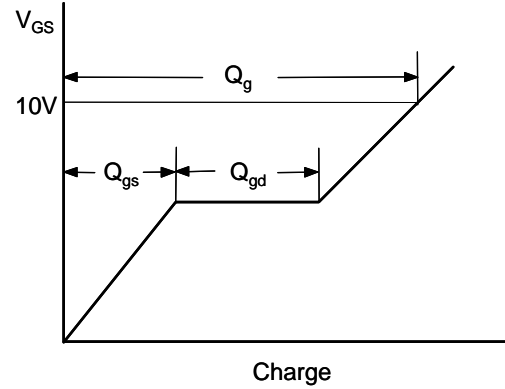
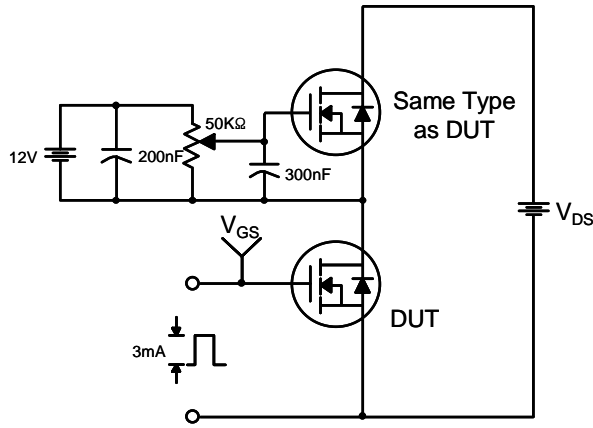
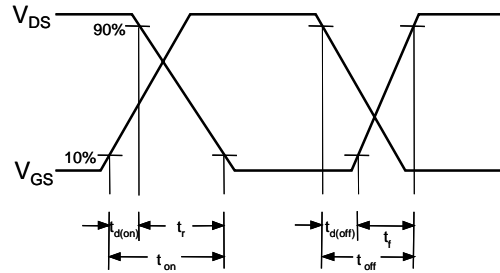
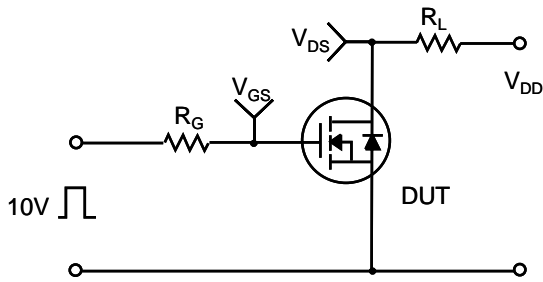


Figure 11. Transient Thermal Response Curve

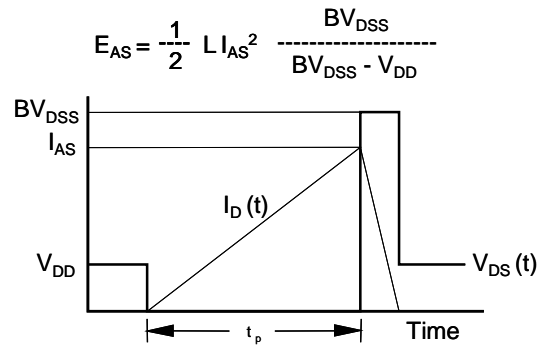
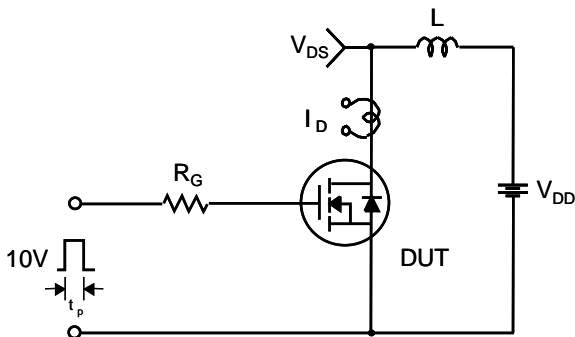
Gate Charge Test Circuit & Waveform



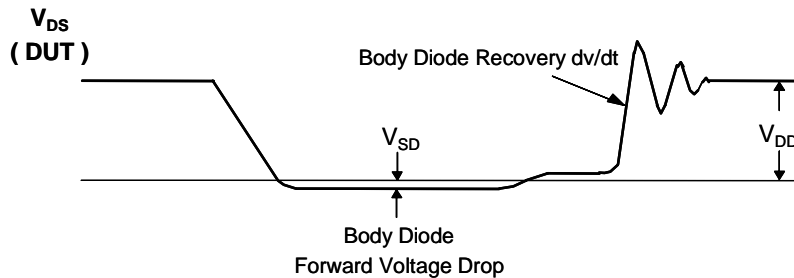
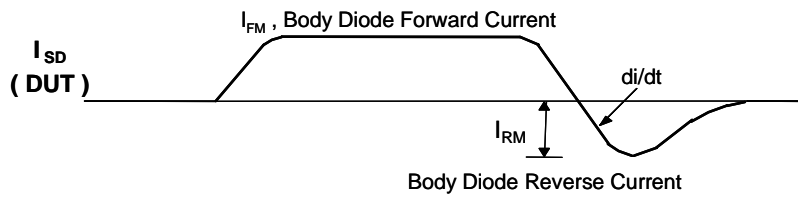
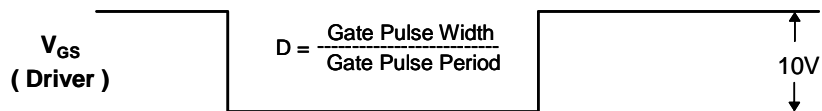
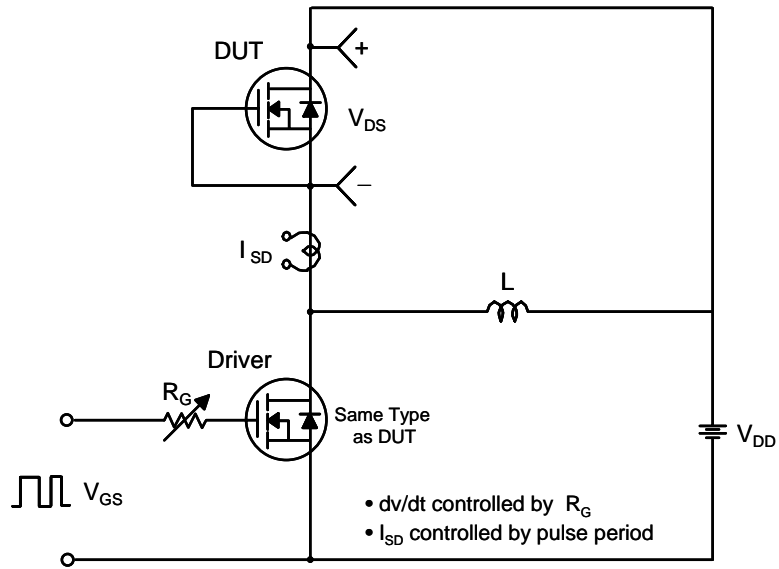
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms



Package Dimension

TO-3P

Unit: mm

